

<b>Notice of References Cited</b>		Application/Control No. 10/823,994	Applicant(s)/Patent Under Reexamination OTA ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-5,282,277 A	02-1994	Onozawa, Shoji	2/69
*	B US-5,367,708 A	11-1994	Fujimoto, Masami	2/22
*	C US-5,465,428 A	11-1995	Earl, Michael S.	2/238
*	D US-D385,385 S	10-1997	Dicker, Timothy P.	D2/731
*	E US-5,727,254 A	03-1998	Dicker, Timothy P.	2/69
*	F US-5,737,773 A	04-1998	Dicker et al.	2/69
*	G US-5,737,772 A	04-1998	Dicker et al.	2/69
*	H US-5,819,322 A	10-1998	Dicker et al.	2/456
*	I US-D404,538 S	01-1999	Fuji et al.	D2/742
*	J US-5,867,827 A	02-1999	Wilkinson, William T.	2/69
*	K US-D413,008 S	08-1999	Fuji et al.	D2/742
*	L US-5,978,966 A	11-1999	Dicker et al.	2/69
*	M US-6,047,405 A	04-2000	Wilkinson, William T.	2/69

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
N					
O					
P					
Q					
R					
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<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination OTA ET AL.	
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**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A US-6,231,488 B1	05-2001	Dicker et al.	482/124
*	B US-D460,602 S	07-2002	Tanaka, Fumiko	D2/742
*	C US-6,430,752 B1	08-2002	Bay, Gregory Steven	2/228
*	D US-D465,078 S	11-2002	Tanaka, Fumiko	D2/742
*	E US-D465,900 S	11-2002	Tanaka, Fumiko	D2/742
*	F US-D466,674 S	12-2002	Tanaka, Fumiko	D2/742
*	G US-6,684,410 B2	02-2004	Robinett et al.	2/228
*	H US-2004/0111781 A1	06-2004	Miyake et al.	002/069
*	I US-D507,857 S	08-2005	Ota et al.	D2/742
*	J US-D508,304 S	08-2005	Ota et al.	D2/742
*	K US-7,229,390 B2	06-2007	Fujii et al.	482/124
*	L US-2007/0214541 A1	09-2007	Kawasaki et al.	002/069
*	M US-2008/0083055 A1	04-2008	Onda, Hironori	2/455

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N				
	O				
	P				
	Q				
	R				
	S				
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